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Application/Control No.	Applicant(s)/Patent under Reexamination
10/687,172	LIN ET AL.
Examiner	Art Unit
Sam K. Ahn	2611

SEARCHED					
Class	Subclass	Date	Examiner		
375	249,274,281 301,327,324 342,344,345 3751376 307,304,308	/18	a		
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INTERFERENCE SEARCHED			
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
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